

1. Record Nr.	UNINA9910484286203321
Autore	Hanagal David D.
Titolo	Software reliability growth models // David D. Hanagal, Nileema N. Bhalerao
Pubbl/distr/stampa	Singapore : , : Springer, , [2021] ©2021
ISBN	981-16-0025-2
Descrizione fisica	1 online resource (115 pages) : illustrations
Collana	Infosys Science Foundation
Disciplina	605
Soggetti	Statistics Estadística Models matemàtics Llibres electrònics
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Includes index.
Nota di contenuto	Intro -- Preface -- Contents -- About the Authors -- List of Figures -- List of Tables -- 1 Introduction to Software Reliability Models -- 1.1 Introduction -- 1.2 Basic Concepts -- 1.3 Software Reliability Models -- 1.4 Failure Rate Models -- 1.5 Model Selection Procedures -- 1.6 Data Sets -- 1.7 Chapterwise Summary -- References -- 2 Literature Survey in Software Reliability Growth Models -- 2.1 Introduction -- 2.2 Non-homogeneous Poisson Process -- 2.3 Delayed S-Shaped Software Reliability Growth Models -- 2.4 Inflection S-Shaped Software Reliability Growth Models -- 2.4.1 Generalized Inflection S-Shaped SRGM -- 2.4.2 Generalized S-Shaped SRGM -- 2.5 Data-Driven Approach -- 2.6 Some More Generalization on SRGM -- References -- 3 NHPP Software Reliability Growth Models -- 3.1 Introduction -- 3.2 Modeling Procedure -- 3.3 Finite Failure Models -- 3.4 Numerical Example -- References -- 4 Inverse Weibull Software Reliability Growth Model -- 4.1 Introduction -- 4.2 Inverse Weibull Finite Failure NHPP Model -- 4.2.1 Software Reliability -- 4.2.2 Confidence Interval -- 4.2.3 Parameter Estimation -- 4.2.4 Goodness-of-Fit Test for the Inverse Weibull Model -- 4.3 Numerical Example -- 4.4 Discussions -- References -- 5 Generalized Inverse Weibull Software Reliability Growth

Model -- 5.1 Introduction -- 5.2 Generalized Inverse Weibull Software Reliability Growth Model -- 5.2.1 Software Reliability -- 5.2.2 Parameter Estimation -- 5.2.3 Goodness of Fit Test for the GIW Model -- 5.3 Numerical Example -- 5.4 Discussions -- References -- 6 Extended Inverse Weibull Software Reliability Growth Model -- 6.1 Introduction -- 6.2 Extended Inverse Weibull NHPP Software Reliability Growth Model -- 6.2.1 Software Reliability -- 6.2.2 Parameter Estimation -- 6.2.3 Goodness of Fit Test for the EIW Model -- 6.3 Numerical Example -- 6.4 Discussions -- References.

7 Generalized Extended Inverse Weibull Software Reliability Growth Model -- 7.1 Introduction -- 7.2 Generalized Extended Inverse Weibull NHPP Software ... -- 7.2.1 Software Reliability -- 7.2.2 Parameter Estimation -- 7.2.3 Goodness-of-Fit Test for the GEIW Model -- 7.3 Numerical Example -- 7.4 Discussions -- References -- 8 Delayed S-Shaped SRGM with Time Dependent Fault Content Rate Function -- 8.1 Introduction -- 8.2 Delayed S-Shaped SRGM -- 8.2.1 Linear Fault Content (or Introduction) Rate Function -- 8.2.2 Quadratic Fault Content (or Introduction) Rate Function -- 8.2.3 Exponential Fault Content (or Introduction) Rate Function -- 8.3 Numerical Example -- 8.4 Discussions -- 8.5 Overall Conclusions -- References -- 9 Scope for Future Extension to SRGM -- 9.1 Introduction -- 9.2 Weighted Inverse Weibull SRGM -- 9.2.1 Software Reliability -- 9.2.2 Confidence Interval -- 9.2.3 Parameter Estimation -- 9.3 Scope for the Research -- References -- Appendix A Index -- Index.

---